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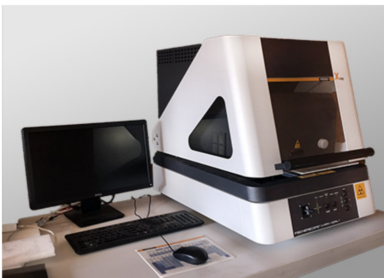
Instant Analysis



Fischerscope XDAL

The Fischerscope XDAL is an x-ray fluorescence (XRF) measurement tool for industrial applications. XRF works by exciting the sample material and detecting the characteristic x-ray emission coming from the sample. The collected data can be used to calculate the material composition or the thickness of a multilayer thin film layer stack of a sample. A motorized XYZ unit allows measurement of profiles or x-y film thickness mappings.

Technical Data	
Detector Lower Limit	P, Atomic Number 15
Limitations Material Analysis Measurement	± 50 ppm
Film Thickness	0,05 - 5000 µm (depends on Element)
Limitations Film Thickness Measurement	No repeated elements in the layer stack
Sample Size	Flat: 600 x 600 x 8 mm 3D: 250 x 250 x 200 mm
X-Y Positioning Automatic Measurement Size	150 x 250 mm